

# Editor's Column

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The best time to plant a tree was 20 years ago. The second best time is now.

*Chinese Proverb*

## *Editorial Letter*

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**T**HE second issue of *Electronics* journal in December 2020 brings new research in the fields of image processing and integrated circuit design but also many challenges caused by the COVID-19 pandemic that affected all the aspects of our lives globally. Unfortunately, COVID-19 also brought away our friend and renowned member of the Editorial Board of the journal "Electronics", prof. Ninoslav Stojadinović who passed away on 25 December 2020. In honor to this great scientist, educator, and influential leader, our founder and honorary Editor-in-Chief, prof. Branko Dokić, accepted to pass to our knowledge at least a tiny part of prof. Stojadinović's rich and fruitful professional life within "In Memoriam" section.

In this issue we have three original research papers.

The first paper "A Novel Unsupervised Approach for Land Classification Based on Touzi Scattering Vector Model in the Context of Very High Resolution PolSAR Imagery," authored by J. Gong, Sheng Sun, and Z. Xu, describes a novel classifying algorithm based on Touzi scattering vector model by means of integrating Touzi decomposition with conventional

Wishart statistical models. The experimental results proved proposed method to be superior to classical method in terms of producer, user and overall accuracy.

The paper "A Full Adder Design with CNFETs for Real Time, Fault Tolerant and Mission Critical Applications," by J. K. Saini, A. Srinivasulu, and R. Kumawat, presents a full adder design with CNFETs that provides high fault resistance towards transient and permanent faults. Moreover, the proposed design enables operation with least power, delay and power-delay product (PDP). Finally, the authors simulated the design at 32 nm technology with 0.9V supply voltage using the Cadence Virtuoso CAD tool.

Finally, the paper "Sensitivity Analysis of the UTBSOI Transistor based Two-Stage Operational Amplifier," by R. U. Ahmed, E. A. Vijaykumar, and P. Saha provides a sensitivity analysis procedure for the CMOS and UTBSOI based two-stage operational amplifiers (OPAMPs) as a function of perturbation in W/L. To this end, the authors proposed an algorithm for computing sensitivity and conducted simulations for a number of scenarios. The results shown that the sensitivity of the UTBSOI based OPAMP is larger than in the case of CMOS based OPAMP.

I thank the authors for their contribution to this issue of the journal and to all the reviewers who participated in the editorial process by providing valuable comments in timely manner to the editors and the authors.